



Optical and Crystallographic Properties of Inverse Opal Photonic Crystals Grown by Atomic Layer Deposition

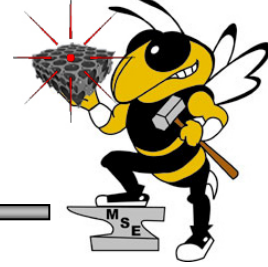
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Research Team



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Outline



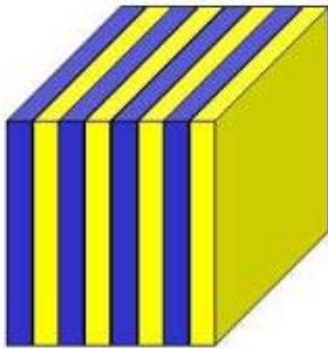
- Introduction: Photonic Crystals
- Fabrication of Luminescent Inverse Opals
- Atomic Layer Deposition
- Results
 - ZnS:Mn controlled infiltration
 - TiO₂ infiltration and heat treatment
 - ZnS/TiO₂ multi-layered structure
- Summary



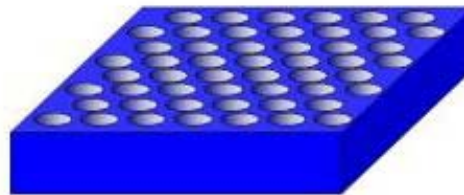
Photonic Crystals



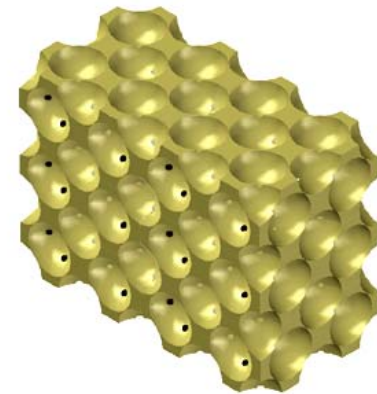
- Photonic Crystal – Periodic modulation of dielectric constant
- Exhibit photonic band gap (PBG).
- Photonic band gap materials can be used to create waveguides, resonators, couplers, filters, etc.
- Luminescent 2D & 3D PC structures offer the potential for controlling wavelength, efficiency, time response and threshold properties (Plasma phosphors, solid state lighting, etc.).



1D



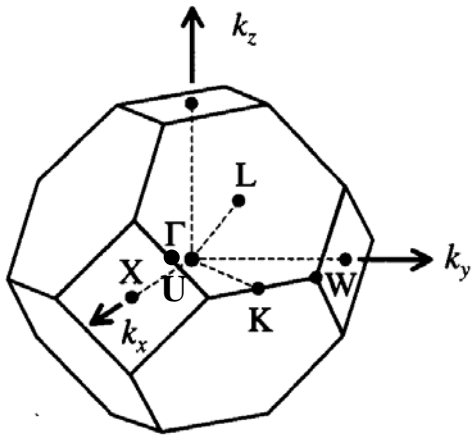
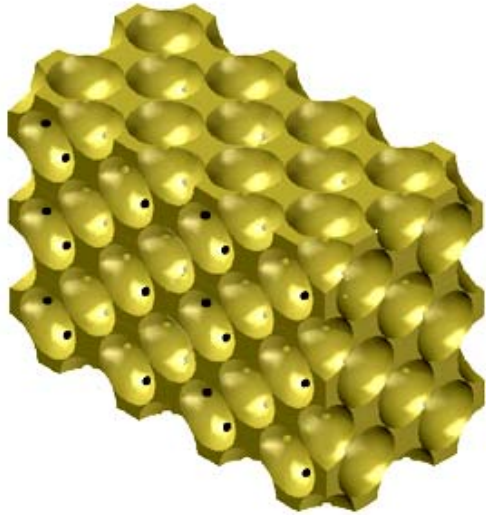
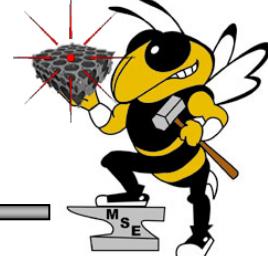
2D



3D

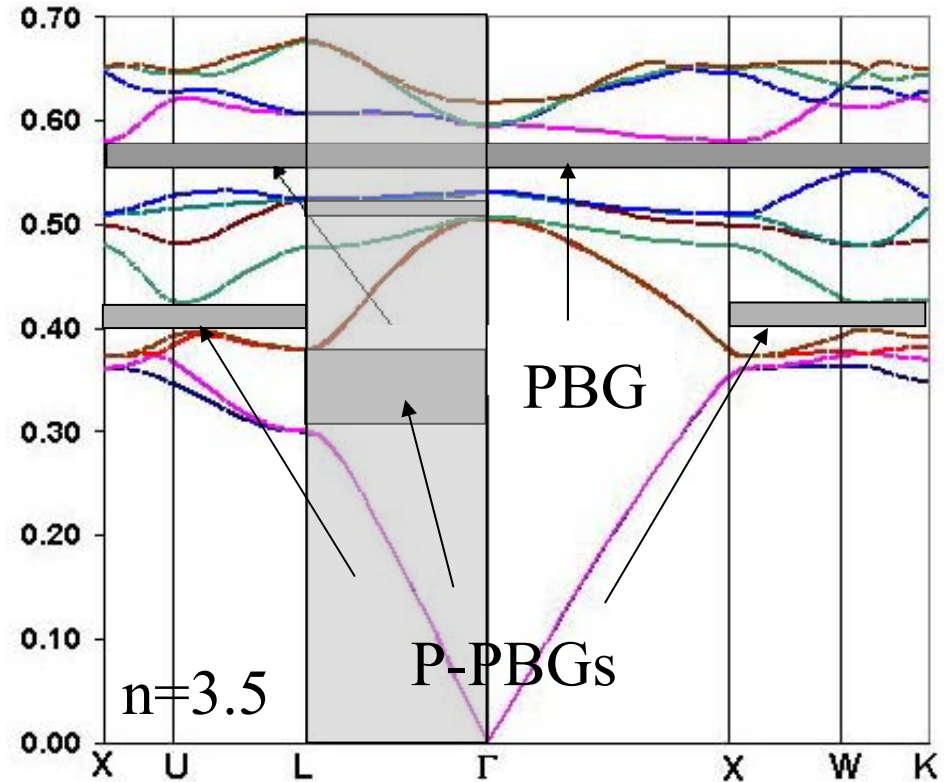
Photonic Crystals

Inverse Opals



FCC Brillouin Zone

Silicon Inverse Opal Photonic Band Diagram



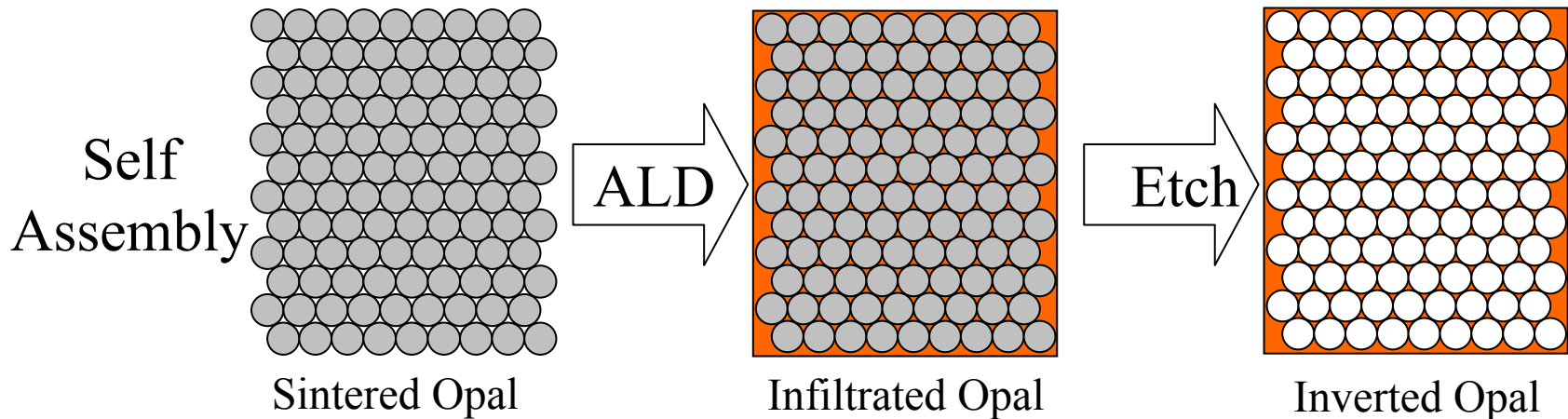
- Reflectance measurements probe photonic band structure: PBG, P-PBG



Fabrication: Inverse Opal PC



- Provide template using self-assembled silica opal.
 - 10 μm thick FCC polycrystalline film, (111) oriented.
- Infiltrate interstitial space with high n material.
 - ZnS:Mn $n \sim 2.5$ @ 425 nm (pseudo photonic band gaps)
 - TiO_2 (rutile) $n_{\text{avg}} \sim 3.08$ @ 425 nm (full photonic band gap possible)
- Etch SiO_2 spheres, forming inverse opal.





Luminescent Photonic Crystals



- Inverse opal - Full PBG if $n > 2.8$
- Most luminescent materials do not offer sufficient index.
- High index, luminescent materials required for PCP
 - Combination of two materials offers practical route.
 - ZnS:Mn (luminescent) + TiO₂ (high n) multi-layer.
- Requires controlled thickness; dense, conformal films.
 - 24.5 % vol. fraction doubles PBG (John & Busch)
 - Atomic Layer Deposition (ALD) fulfills requirements.



Atomic Layer Deposition



ALD is a CVD growth technique utilizing sequential reactant pulses.

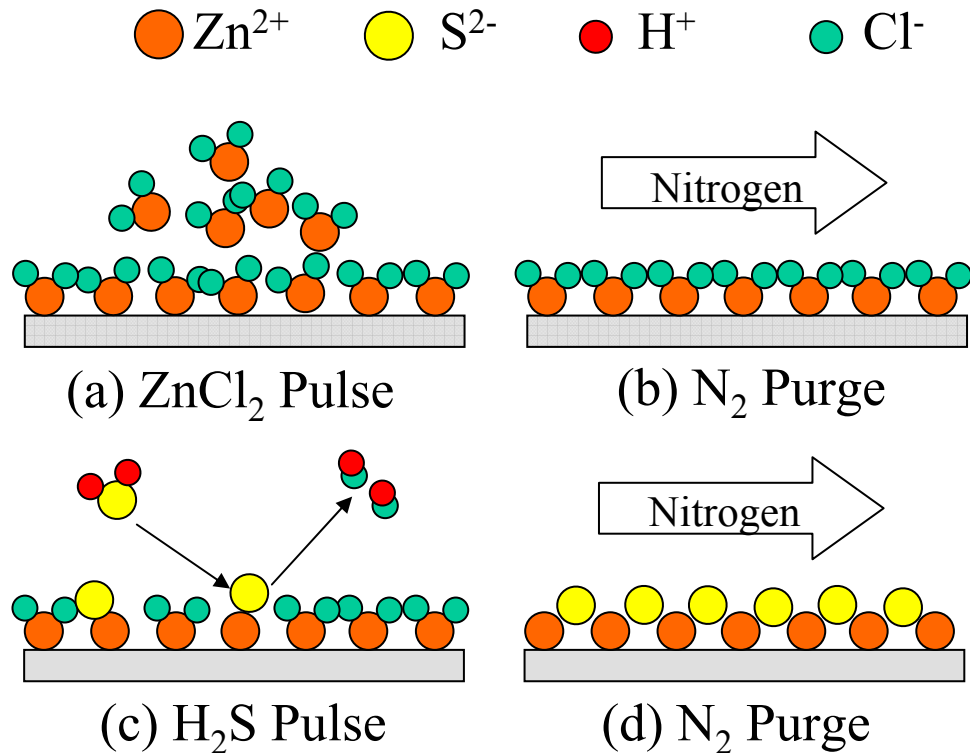
ALD Growth of ZnS

(a) Chemi + physisorption

(b) Physisorbed layer removal

(c) Formation of ZnS

(d) Removal of H₂S and HCl



Surface limited growth: conformal films + monolayer control



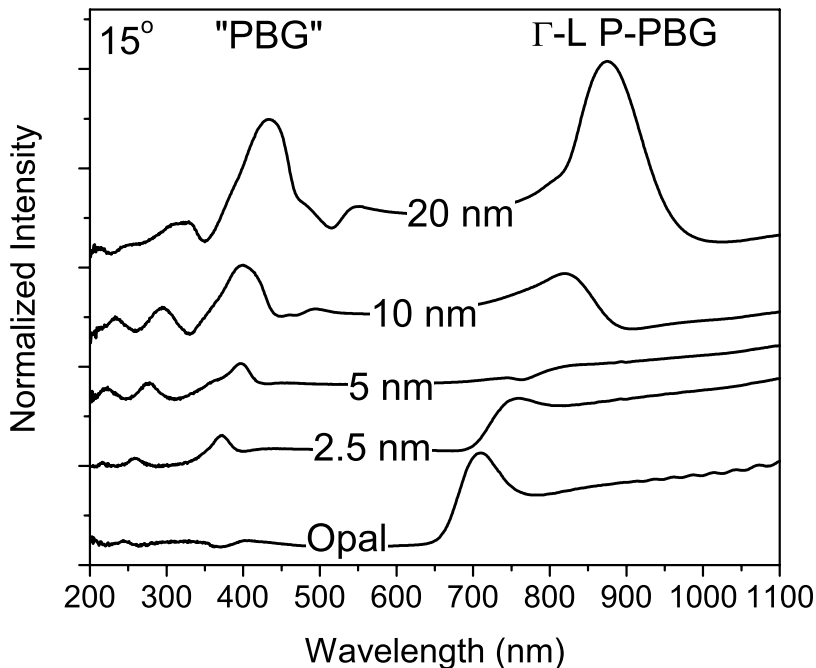
ZnS:Mn Stepwise Infiltration



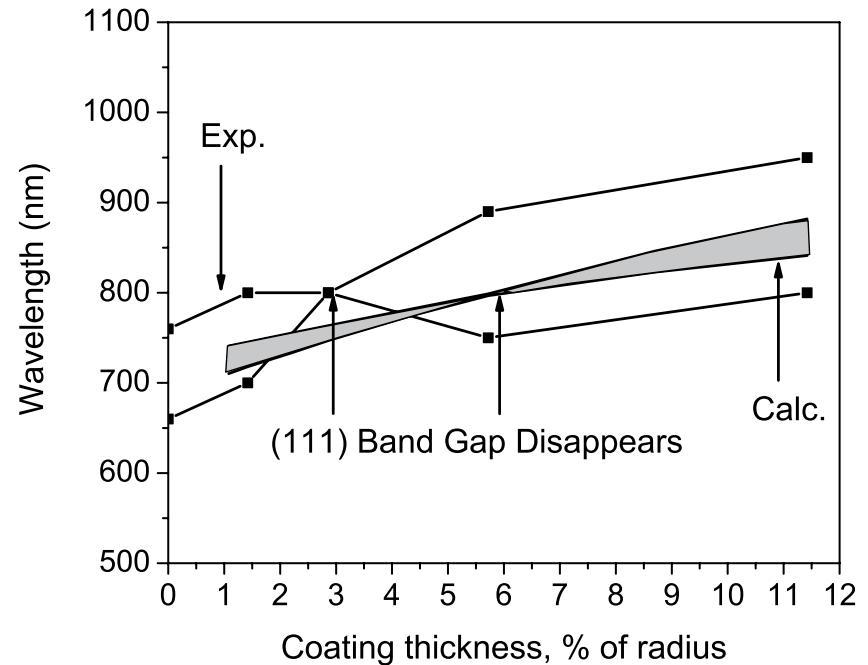
- Previously demonstrated ZnS:Mn full infiltration (MRS 2002, APL 83).
- However, multi-layered opals require infiltration finesse.
- 330 and 460 nm opals were filled with increasing % of ZnS:Mn.
- Deposition @ 500° C with a MnCl₂ doping pulse every 32 cycles.
- Shift of P-PBG to longer wavelengths shown in specular reflectance after infiltrations.



ZnS:Mn Stepwise Infiltration



Specular reflectance



Γ -L gap positions

Deviation from theory:

- Coating thickness based on planar growth, not curved surface.
- Reflectivity measured @ 15° from normal.



TiO₂ Infiltration



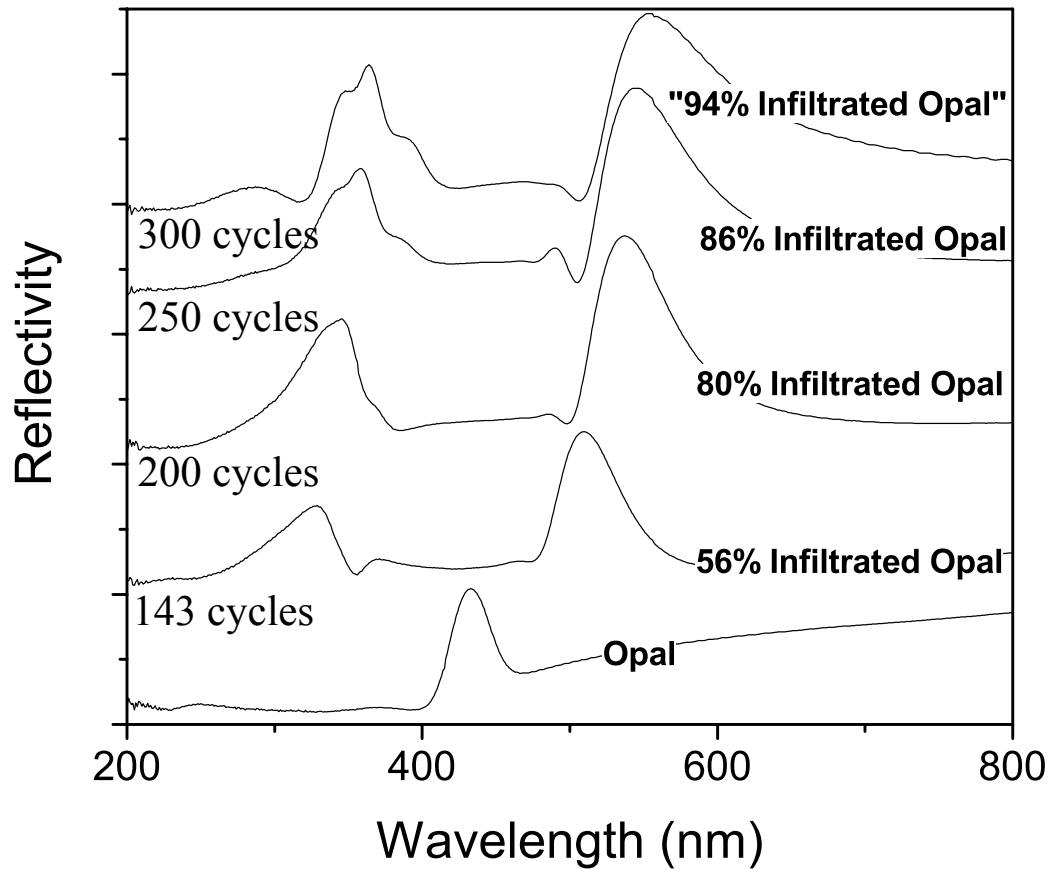
- **Need to demonstrate ability to grow high index component by ALD.**
- Aarik, et.al. have shown in planar ALD TiO₂ growth studies:
 - <165° C = amorphous, 165° - 350° C = anatase, >350° C = rutile
- TiO₂ was infiltrated using TiCl₄ and H₂O pulses.
- Amorphous film growth has advantages over crystalline:
 - **Amorphous films exhibit very smooth surfaces.**
 - Better suited for the conformal infiltration of opals
- Infiltrate at low T, then heat treat to obtain rutile (high index).
- Infiltrations were performed at both 100° C and 500° C.
- Inverse opal formation
 - For amorphous film, ion mill to expose silica (very conformal).



TiO₂ Infiltration



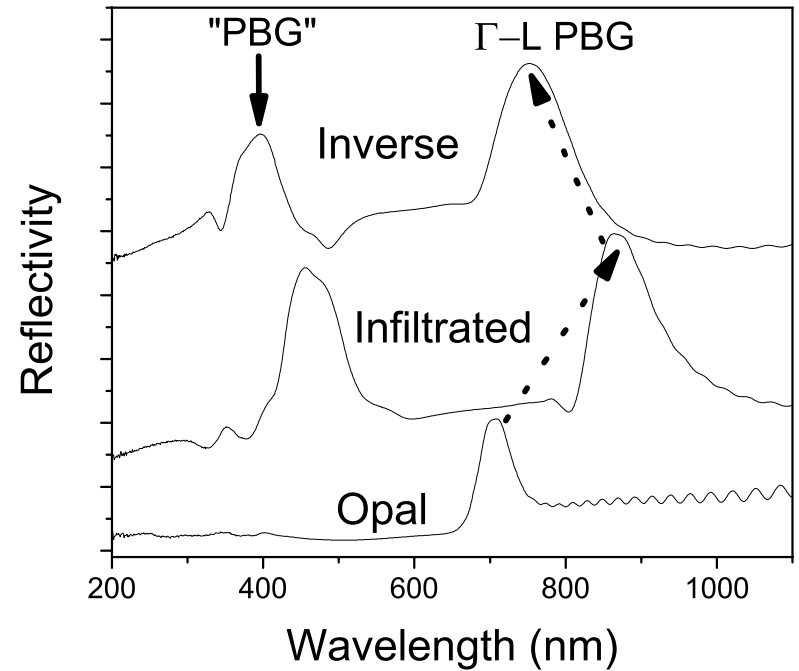
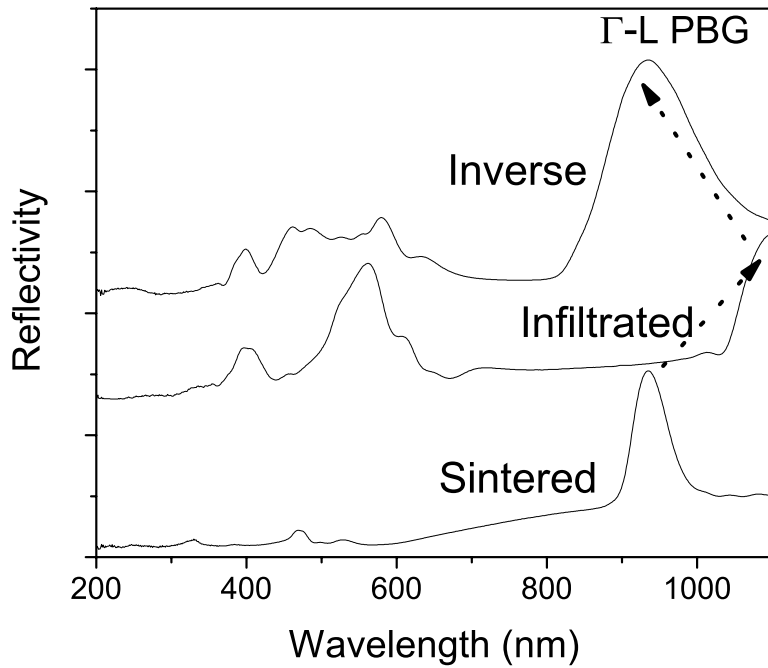
Si058 (200 nm Opal)

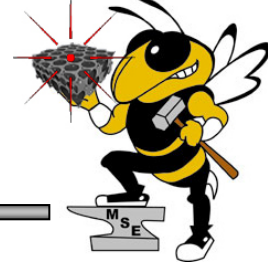




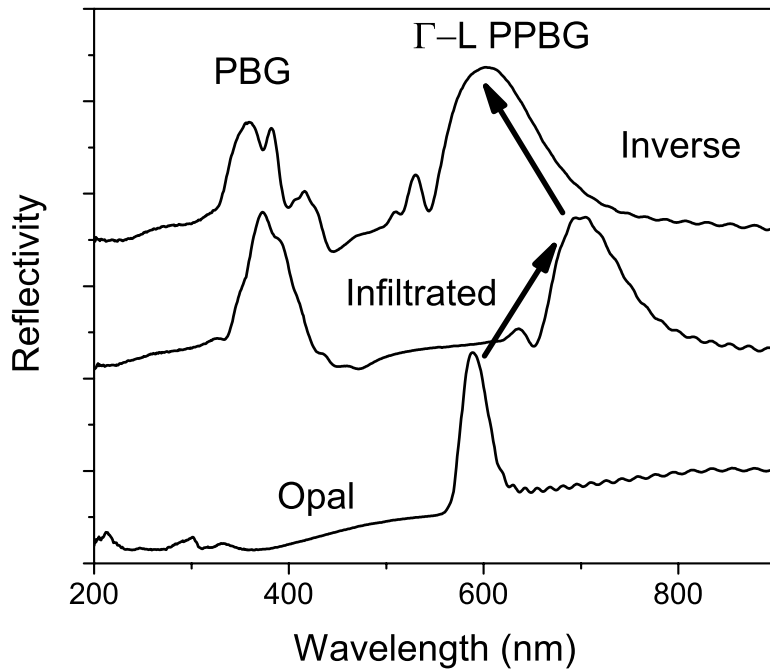
Si090A (430 nm)

Si091D (330 nm)



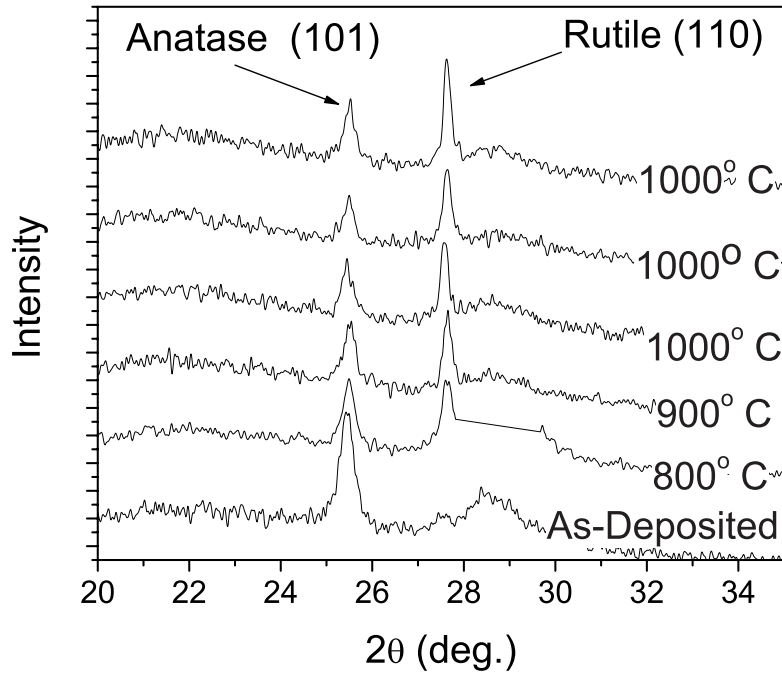


Si083 (273 nm)

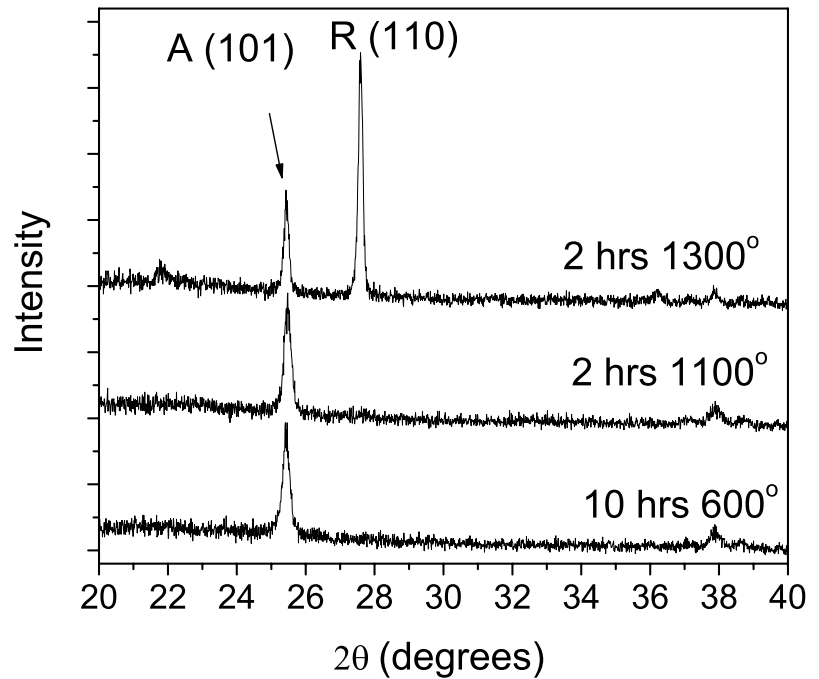




TiO₂ Rutile Conversion - XRD



Deposited at 500° C
(initially anatase).
~50% rutile after HT



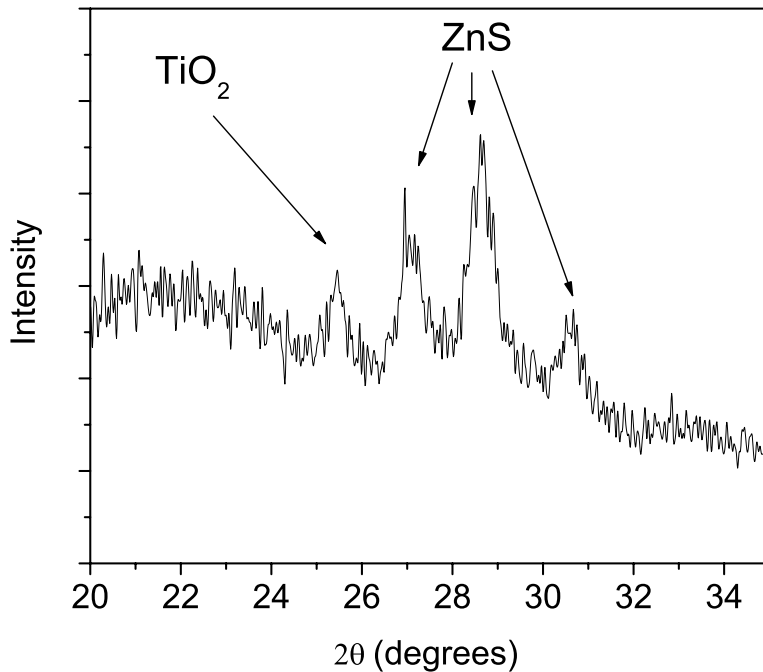
Deposited at 100° C
(initially amorphous).
~65% rutile after HT



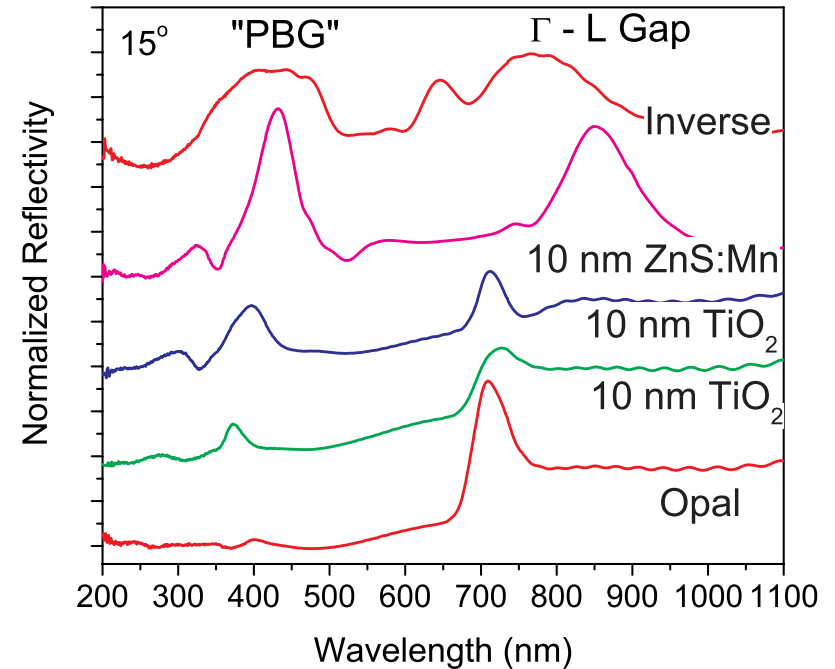
ZnS/TiO₂ Inverse Opal



- TiO₂ at deposited at 100° C, ZnS:Mn at 500° C.
- Amorphous TiO₂ converts to anatase during ZnS:Mn growth.



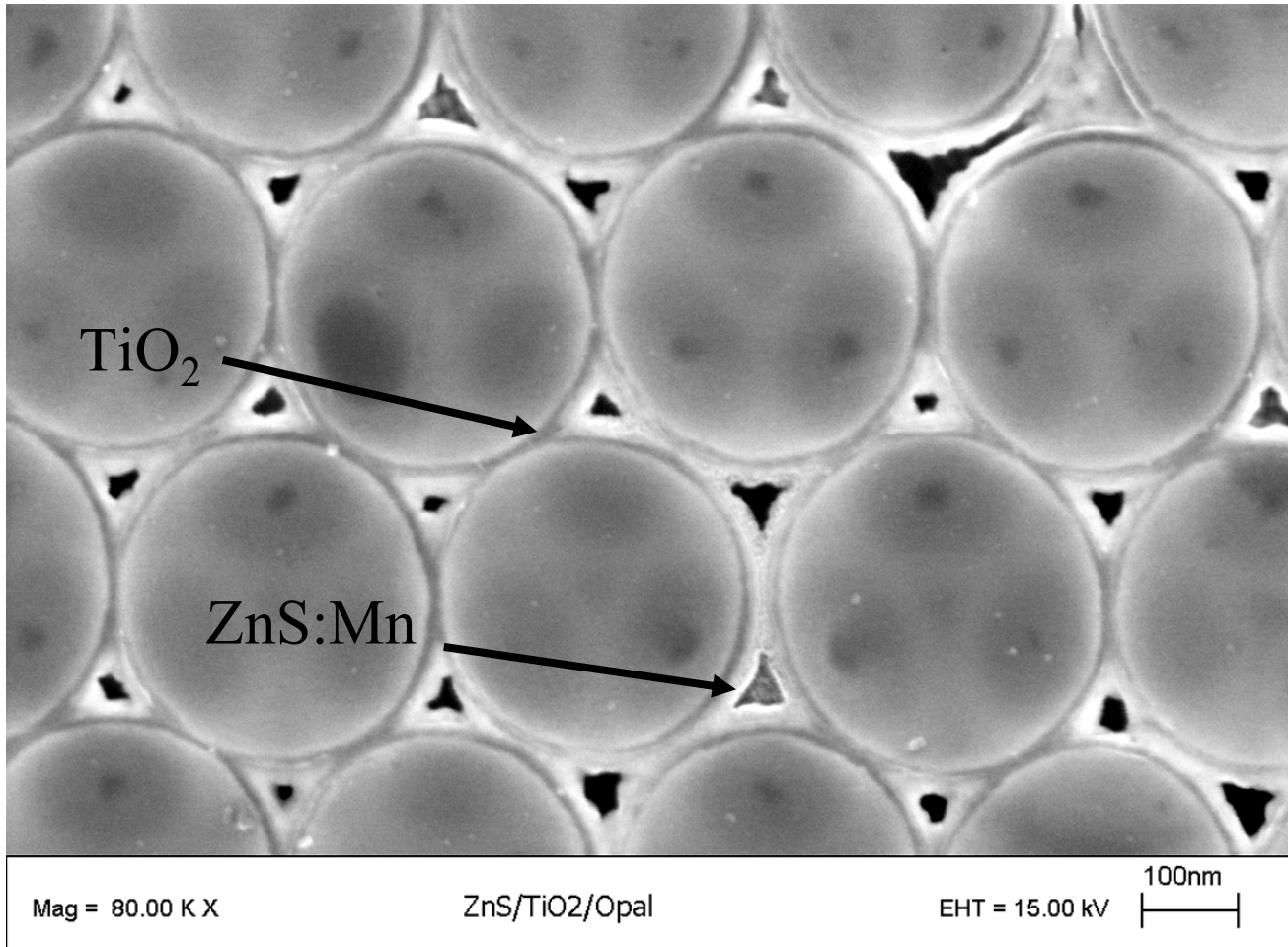
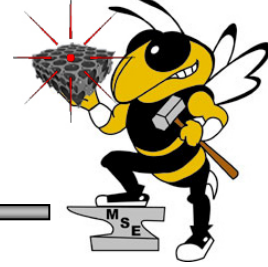
XRD



Specular Reflectance



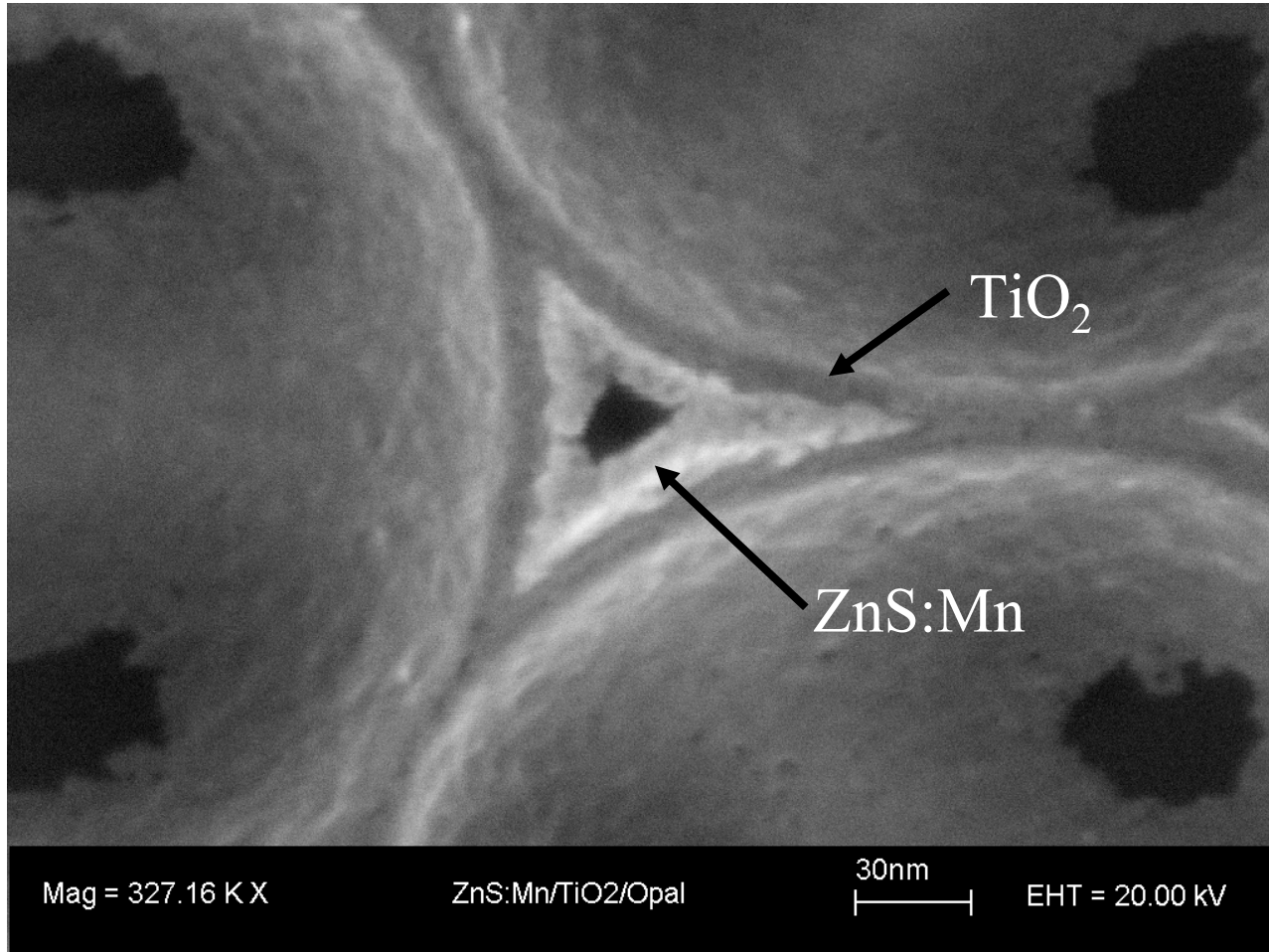
ZnS/TiO₂ Infiltrated Opal



ZnS:Mn/TiO₂ multi-layered 330 nm infiltrated opal



ZnS/TiO₂ Inverse Opal



ZnS:Mn/TiO₂ multi-layered 330 nm inverse opal.



Summary



- Successful formation of ZnS:Mn and TiO₂ inverse opals.
- **Precise control of ALD infiltration demonstrated.**
- As-deposited TiO₂ **can be converted to rutile phase.**
- Clearly demonstrated **ability to grow complex *luminescent PC structures*** at the nanoscale using ALD.
- Future: PL measurements, RTA, more complex structures.



Acknowledgements



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